

A Physical Approach for Stochastic Modeling of TERO-based TRNG

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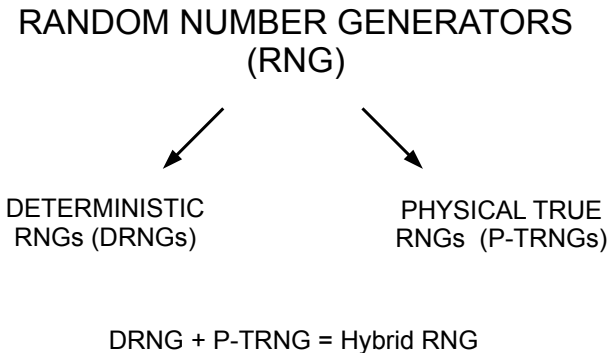
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Random numbers in cryptography

- ▶ Random number generators constitute an essential part of (hardware) cryptographic modules
- ▶ The generated random numbers are used as:
 - Cryptographic keys (high security requirements)
 - Masks in countermeasures against side channel attacks
 - Initialization vectors, nonces, padding values, ...



Classical versus modern TRNG evaluation approach

- ▶ Two main security requirements on RNGs:
 - R1: Good statistical properties of the output bitstream
 - R2: Output unpredictability
- ▶ Classical approach:
 - Assess both requirements using statistical tests – often impossible
- ▶ Modern ways of assessing security:
 - Evaluate statistical parameters using statistical tests
 - Evaluate entropy using entropy estimator (stochastic model)
 - Test online the source of entropy using dedicated statistical tests

Our objectives

Propose a stochastic model of TERO-based TRNG ^a

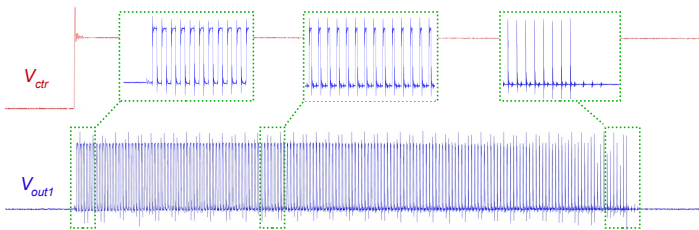
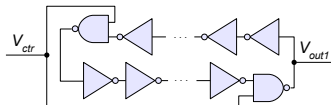
- Based on physical parameters quantifiable inside the device
- Can be used for online entropy assessment

^a M. Varchola and M. Drutarovsky, *New high entropy element for FPGA based true random number generators*, CHES 2010

Transition effect ring oscillator (TERO)

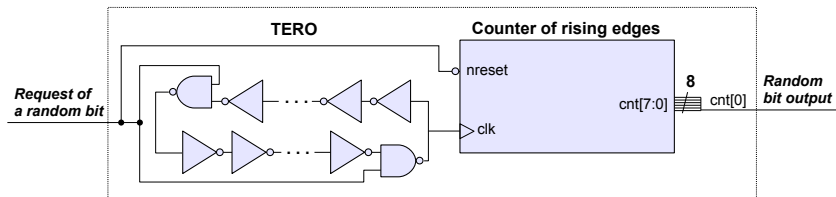
Principle:

- ▶ Even number of inverters and two control gates in a loop
- ▶ Oscillates temporarily because of the difference in two branches
- ▶ Number of oscillations varies because of the intrinsic noise



TERO-based P-TRNG

Implementation:



- ▶ An asynchronous 8-bit counter counts random number of oscillations
- ▶ We use the counter to characterize the TERO
- ▶ The LSB of the counter ($cnt(0)$) is used also as the random bit (TRNG output)

Outlines of the modeling

Since the P-TRNG is periodically restarted, the counter values are mutually independent, therefore:

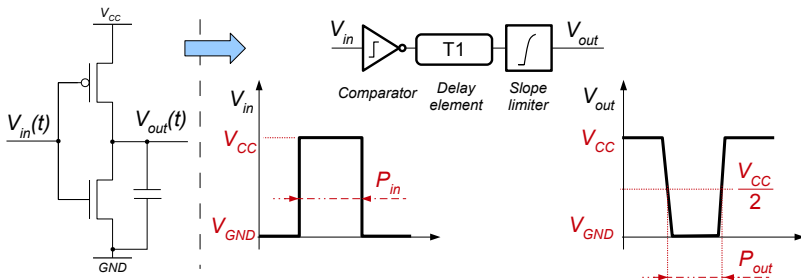
$$\text{Entropy} = -p_1 \cdot \log_2(p_1) - (1 - p_1) \cdot \log_2(1 - p_1),$$

where $p_1 = Pr\{cnt(0) = 1\}$.

We want to determine p_1 , therefore, we need to analyze and characterize the distribution of counter values.

A noiseless inverter

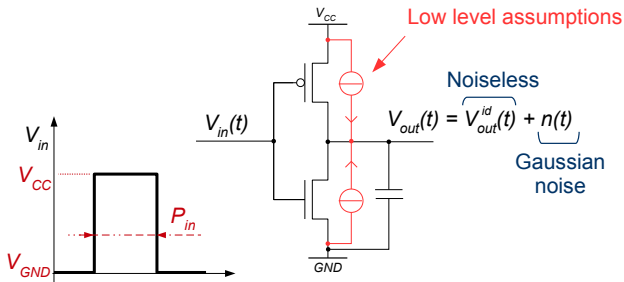
Behavior of a noiseless inverter:



Analyzed by Reyneri *et al.*,² they determined $P_{out} = f(P_{in})$

A noisy inverter

Behavior of a noisy inverter:

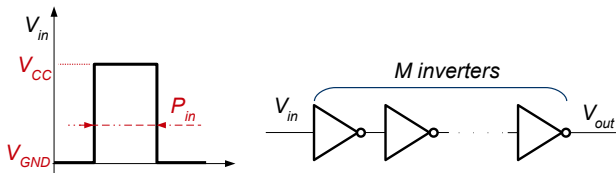


In the paper, using the model of Reyneri *et al.*, we determine

$$P_{out} \sim \mathcal{N}(f(P_{in}), \sigma^2) \text{ (see Lemma 1)}$$

An chain of M inverters

Impact of the noise on a chain of inverters:

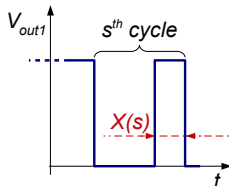
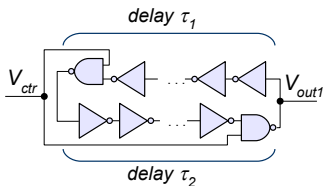


We apply *Lemma 1* to each inverter of the chain

We obtain $P_{out} \sim \mathcal{N}(F(P_{in}, M), G(\sigma^2, M))$

A loop of inverters

Impact of the noise on the duty cycle:



$$X(s) \sim N\left(\frac{\tau_1 + \tau_2}{2} + \underbrace{\frac{\tau_2 - \tau_1}{2} \cdot R^s}_{\text{Geometric series (ratio } R\text{)}}, \sigma^2 \cdot \frac{R^{2s+1} - 1}{(1 + H_d)^2 - 1}\right)$$

Stochastic model of TERO P-TRNG

The model characterizes distribution of counter values

- ▶ Objective: We want to get $Pr\{cnt = s\}$
- ▶ We just know the distribution of $X(s)$

We can use the equivalence $cnt > s \iff X(s) > 0$

Then

$$Pr\{cnt > s\} = \frac{1}{2} \left[1 - \operatorname{erf} \left(K \cdot \frac{1 - R^{s-s_0}}{\sqrt{R^{2s+1} - 1}} \right) \right]$$

R is the ratio of the geometric series

K reflects the jitter σ^2

s_0 reflects the difference $\tau_1 - \tau_2$

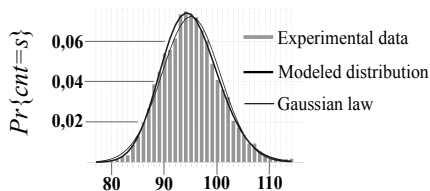
and

$$Pr\{cnt = s\} = Pr\{cnt \leq s\} - Pr\{cnt \leq s + 1\}$$

Experimental validation

Validation of the modeled distribution using a χ^2 test

Experiment: TERO 1 in an ST Microelectronics 28 nm ASIC



$$K = 35,680$$

$$s_0 = 94,152$$

$$R = 1,0153$$

For a significance level $\alpha = 0.05$ and 38 degrees of freedom, the test statistic has to be lower than 53.384

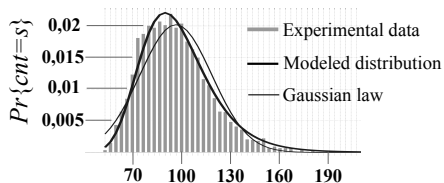
Our model: the test statistic is 40.35

Gaussian law: the test statistic is 149.3

Experimental validation

Validation of the modeled distribution using a χ^2 test

Experiment: TERO 2 in an ST Microelectronics 28 nm ASIC



$$K = 9,6939$$

$$s_0 = 90,675$$

$$R = 1,013$$

For a significance level $\alpha = 0.05$ and 76 degrees of freedom, the test statistic has to be lower than 97.351

Our model: the test statistic is 33.97

Gaussian law: the test statistic is $> 10^6$

Entropy estimation

From our physical analysis we know $Pr\{cnt = s\}$

From $Pr\{cnt = s\}$ we compute $p_1 = Pr\{cnt(0) = 1\}$

Recall: Since the TERO is periodically restarted, the subsequent counter values are mutually independent and thus

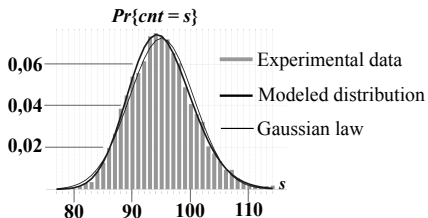
$$H_{sample} = - \sum_{s \in \mathbb{N}} p_s \log_2(p_s)$$

$$H_{lsb} = -p_1 \cdot \log_2(p_1) - (1 - p_1) \cdot \log_2(1 - p_1)$$

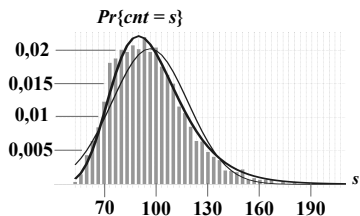
The second term represents the entropy of our TERO P-TRNG

Estimated entropy

Application of the model to TERO 1 and TERO 2



$$\begin{aligned}
 K &= 35,680 \\
 s_0 &= 94,152 \\
 R &= 1,0153 \\
 H_{sample} &= 4,47 \\
 H_{lsb} &> 0,999
 \end{aligned}$$



$$\begin{aligned}
 K &= 9,6939 \\
 s_0 &= 90,675 \\
 R &= 1,013 \\
 H_{sample} &= 6,32 \\
 H_{cnt(0)} &> 0,999
 \end{aligned}$$

- ▶ In the two cases the entropy of the raw binary signal exceeds the value 0.997 required by AIS31
- ▶ All generated bit streams passed tests T0 to T8 of AIS 31

Conclusions

- ▶ We presented a **stochastic model** of the TERO P-TRNG
- ▶ The model is based on **transistor-level assumptions**
- ▶ The model was **validated** in an ASIC implemented using 28 nm ST Microelectronics technology
- ▶ We derived the **entropy** from this model
- ▶ The entropy and the output bit rate can be **easily managed** using the model

